

METHOD OF DEFECT ROOT CAUSE ANALYSIS

Appl. No.	:	10/708,943	Confirmation No.	2942
Applicant	:	Long-Hui Lin		
Filed	:	April 2, 2004		
TC/A.U.	:	2857		
Examiner	:	GUTIERREZ, ANTHONY		
Docket No.	:	LKSP0028USA		
Customer No.	:	27765		

Commissioner for Patents
P.O. Box 1450
Alexandria VA 22313-1450

AMENDMENT

Sir:

5 In response to the Office action of February 26, 2008, please amend the above-identified application as follows:

Remarks/Arguments begin on page 2 of this paper.